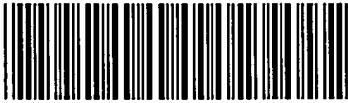


Search Notes

Application/Control No.

10/669,212

Examiner

Chris C. Chu

Applicant(s)/Patent under
Reexamination

KIM ET AL.

Art Unit

2815

SEARCHED

Class	Subclass	Date	Examiner
257	714, 723, 686 & 777	8/2/2005	C.C.

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Searched in USPAT; US-PGPUB; USOCR; EPO; JPO; DERWENT; and IBM_TDB;	8/2/2005	C.C.